Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | PARK ET AL. | Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0027259	03-2002	Ikemasu et al.	257/499
	В	US-2002/0030222	03-2002	Agarwal, Vishnu K.	257/310
	O	US-2002/0034877	03-2002	Shin et al.	438/694
	۵	US-5,817,562	10-1998	Chang et al.	438/305
	Е	US-6,403,413	06-2002	Hayano et al.	438/238
	F	US-2001/0045589	11-2001	Takeda et al.	257/297
	G	US-2001/0041406	11-2001	Goebel et al.	438/255
	Ι	US-			
	1	US-			
	J	US-			
·	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	Ō					
	Р	·				
	a					
	R					
	S			١		
	Т				·	

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.